TECHNICAL SPEC FOR Inspection system

System Model:
KLA 6220

Wafer size: 6 inch

SECS/GEM: yes

Vintage: 2000

Missing parts: none

Defected parts: none

SURFSCAN	Metrology & Inspection	meas def unpatterned	S6200	PB4	0692-189	1992
SURFSCAN2	Metrology & Inspection	meas def patterned	S7700	PB6	0495-516	1995
SURFSCAN3	Metrology & Inspection	meas def unpatterned	S6220	PB25	0897-292	2000
SURFSCAN4	Metrology & Inspection	meas def patterned	S7700 - zone3	PB33	0796-807	1996
SURFSCAN5	Metrology & Inspection	meas def patterned	AIT	PB2	1297-8156 (UTID 1100313)	
SURFSCAN6	Metrology & Inspection	meas def patterned (GaN)	S7700 - zone3	PB33	0696-769	1996
SURFSCAN7	Metrology & Inspection	meas def unpatterned	S6220 - zone3	PB32	0996-227	1996
SURFSCAN8	Metrology & Inspection	meas def patterned	AIT XP+	PB2	9282 (UTID 1129282)